

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MT22-1951SERIAL NO.  
10/086,942

DEC 14 2004

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PARENT &amp; TRADEMARKS

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March 1, 2002 [RCE filed herewith]GROUP  
2813

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CC	AM	EP 0 835 950 A1	04/98	EPO				
CC	AN	0 474 140 A1	03/92	EPO				
	AO							
	AP							
	AO							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR		
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AT		

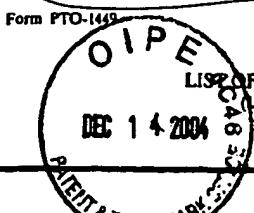
EXAMINER *Chandra Chaudhari* DATE CONSIDERED

2-05

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Form PTO-1449

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1931SERIAL NO.  
10/086,942LIST OF ART CITED BY APPLICANT  
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## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
CC	AA	4,261,698	04/81	Carr et al.			
	AB	4,691,662	09/87	Roppel et al.			
	AC	5,261,961	11/93	Takasu et al.			
	AD	5,270,241	12/93	Dennison et al.			
	AE	5,312,783	03/94	Takasaki et al.			
	AF	5,392,189	02/95	Fazan et al.			
	AG	5,395,771	03/95	Nakato			
	AH	5,468,687	11/95	Carl et al.			
	AI	5,525,156	06/96	Mansada et al.			
	AJ	5,614,018	03/97	Azuma et al.			
	AK	5,656,329	08/97	Hampden-Smith			
↓	AL	5,663,089	09/97	Tomozawa et al.			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CC	AM	EP 0 030 798	06/81	EPO - Hughes				N/A
CC	AN	GB 2 194 555 A	03/88	UK - Nippon				N/A
CC	AO	EP 0 306 069 A2	03/89	EPO - Phillips				N/A
	AP							
	AQ							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

CC	AR	Aoyama et al., "Leakage Current Mechanism of Amorphous and Polycrystalline Ta <sub>2</sub> O <sub>x</sub> Films Grown by chemical Vapor Deposition,"					
		1995, pages 977-983.					
CC	AS	Stemmer et al., "Accommodation of nonstoichiometry in (100) fiber-textured ... thin films grown by chemical vapor deposition,"					
		©1999 American Institute of Physics, pages 2432-2434.					
CC	AT	Streiffer et al., "Ferroelectricity in thin films: The dielectric response of fiber-textured ... thin films grown by chemical vapor deposition,"					
		©1999 American Institute of Physics, pages 4565-4575.					

EXAMINERS

Chandra Chaudhari

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Sheet 2 of 3

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(Use several sheets if necessary)ATTY. DOCKET NO.  
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March 1, 2002GROUP  
2813

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
CC	AA	5,702,562	12/97	Wakahara			
	AB	5,719,417	02/98	Roeder et al.			
	AC	5,723,361	03/98	Azuma et al.			
	AD	5,736,759	04/98	Haushalter			
	AE	5,976,990	11/99	Mercaldi et al.			
	AF	5,989,927	11/99	Yaimonobe			
	AG	6,101,085	08/00	Kawahara et al.			
	AH	6,215,650	04/01	Gaade et al.			
	AI	6,258,654	07/01	Gochio			
	AJ	6,287,933	09/01	Coursey			
	AK	6,325,017 B1	12/01	DeBoer et al.			
▼	AL	6,335,049 B1	01/02	Basceri			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CC	AM	JP 04-24922	01/92	Japan - Mitsubishi				X
CC	AN	JP 04-115533	04/92	Japan - Oki Elec.				X
CC	AO	JP 04-180566	06/92	Japan - Mitsubishi				ABS
CC	AP	JP 08-060347	03/96	Japan - Fujitsu				X
CC	AQ	EP 0 810 666 A1	12/97	EPO - Oki Electric				N/A

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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Chandra Chaudhari

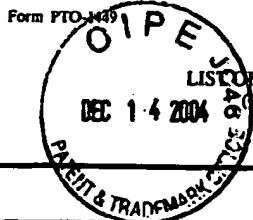
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Sheet 3 of 3



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				FILING DATE March 1, 2002		GROUP 2813		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
CC	AA	6,566,147 B2	05/03	Basceri et al.				
	AB							
	AC							
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	AE							
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
CC	AM	EP 0 892 426 A2	01/99	EPO - Ramtron			Yes	No
CC	AN	WO 01/16395	03/01	WIPO - Micron			N/A	
	AO						N/A	
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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